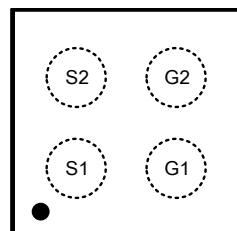


## WNMD2171

### Dual N-Channel, 20V, 6.0A, Power MOSFET

[Http://www.sh-willsemi.com](http://www.sh-willsemi.com)

V <sub>SSS</sub> (V)	Typ R <sub>SS(ON)</sub> (mΩ)
20	38@ V <sub>GS</sub> =4.5V
	39@ V <sub>GS</sub> =4.0V
	42@ V <sub>GS</sub> =3.1V
	46@ V <sub>GS</sub> =2.5V
ESD Rating:2000V HBM	



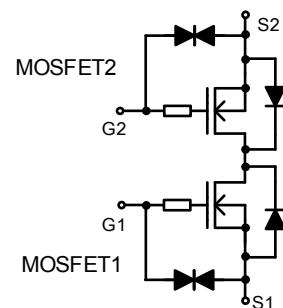
CSP-4L(Top view)

### Descriptions

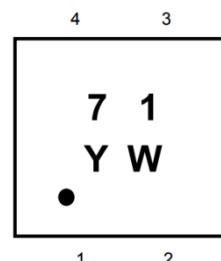
The WNMD2171 is Dual N-Channel enhancement MOS Field Effect Transistor and connecting the Drains on the circuit board is not required because the Drains of the MOSFET1 and the MOSFET2 are internally connected. Uses advanced trench technology and design to provide excellent R<sub>SS(ON)</sub> with low gate charge. This device is designed for Lithium-ion battery protection circuit. The WNMD2171 is available in CSP-4L package. Standard Product WNMD2171 is Pb-free and Halogen-free.

### Features

- Trench Technology
- Supper high density cell design
- Excellent ON resistance
- Extremely Low Threshold Voltage
- Small package CSP 4L



Pin configuration



- 1: Source1    71 = Device Code  
 2: Gate1    Y = Year  
 3: Gate2    W = Week(A~z)  
 4: Source2

Marking

### Order information

Device	Package	Shipping
WNMD2171-4/TR	CSP-4L	3000/Reel&Tape

### Applications

- Lithium-Ion battery protection circuit

**Absolute Maximum ratings**

<b>Parameter</b>	<b>Symbol</b>	<b>Steady State</b>	<b>Unit</b>
Source to Source Voltage ( $V_{GS} = 0$ V)	$V_{SSS}$	20	V
Gate to Source Voltage ( $V_{SS} = 0$ V)	$V_{GSS}$	$\pm 12$	
Source Current (pulse) <sup>Note.c</sup>	$I_{S(pulse)}$	60	A
Source Current (DC)	$I_S$	6	A
Channel Temperature	$T_{ch}$	150	°C
Storage Temperature Range	$T_{stg}$	-55 to 150	°C

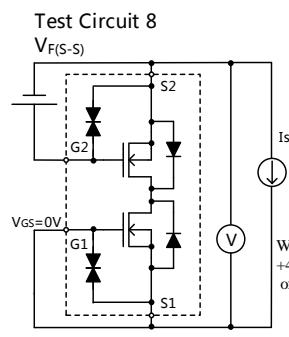
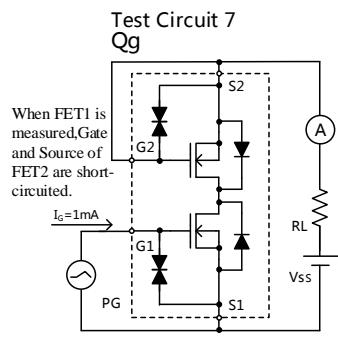
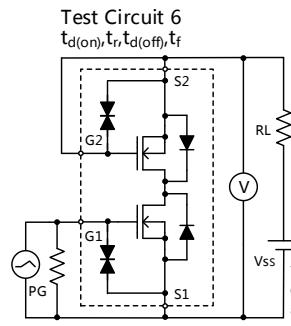
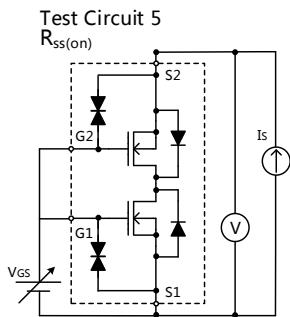
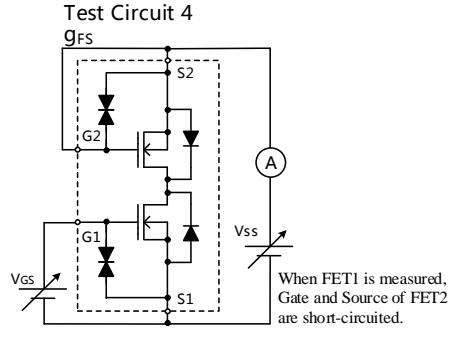
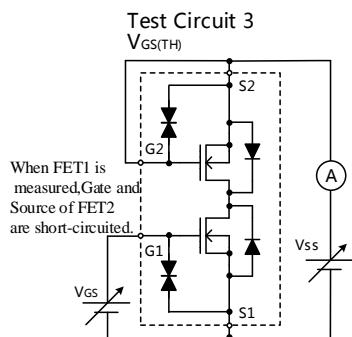
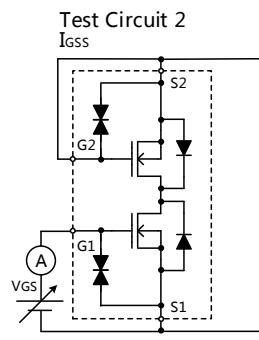
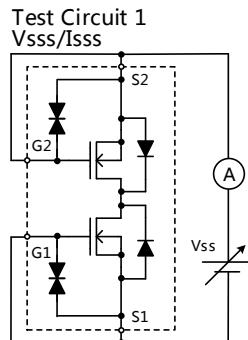
Note.c PW≤10μs, duty cycle≤1%;

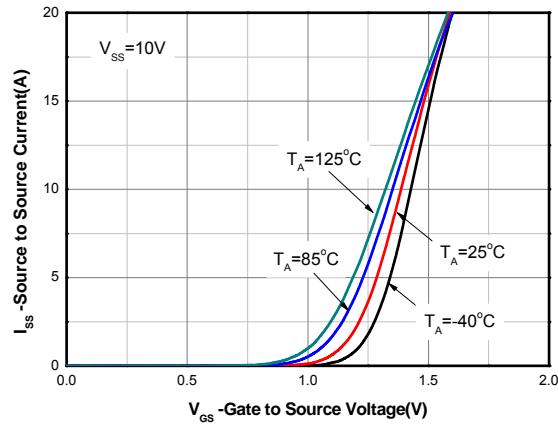
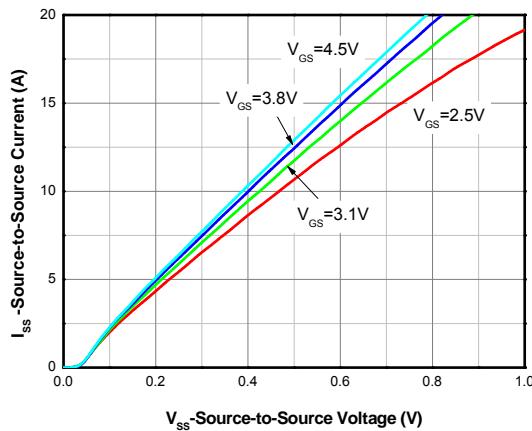
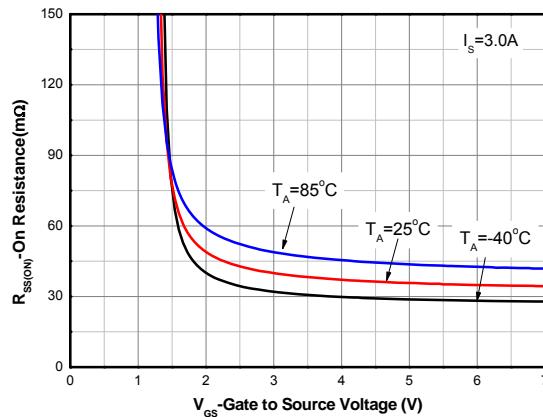
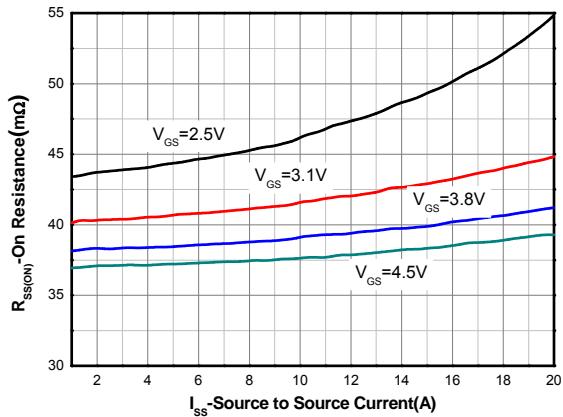
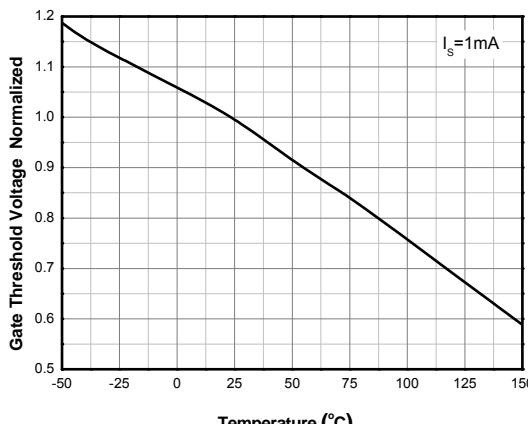
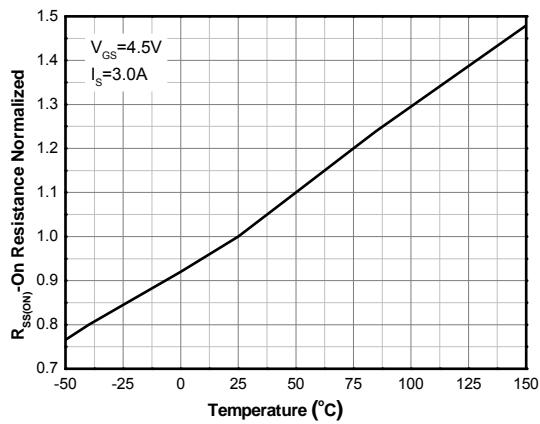
**Electronics Characteristics (Ta=25°C, unless otherwise noted)**

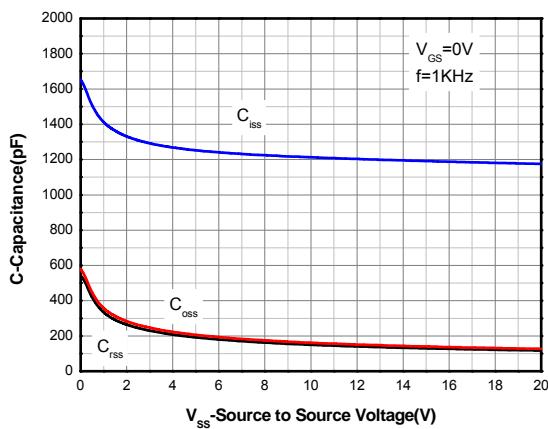
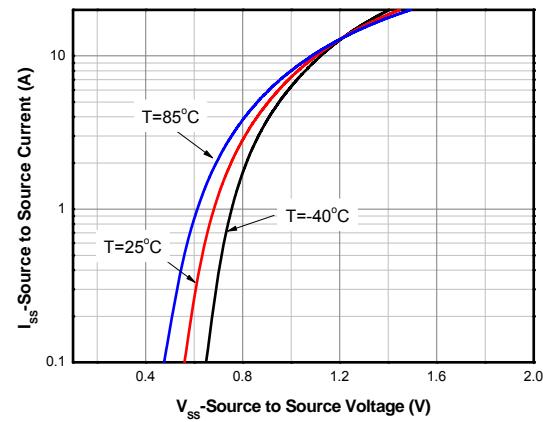
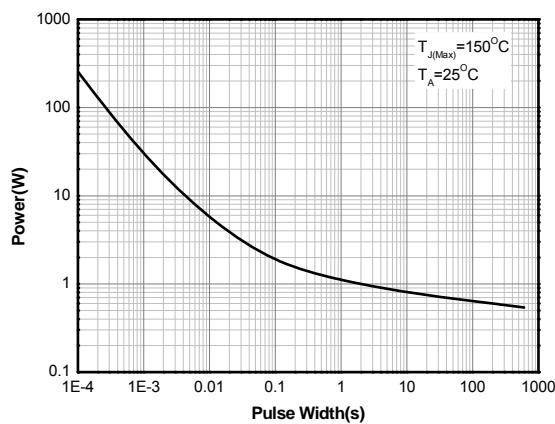
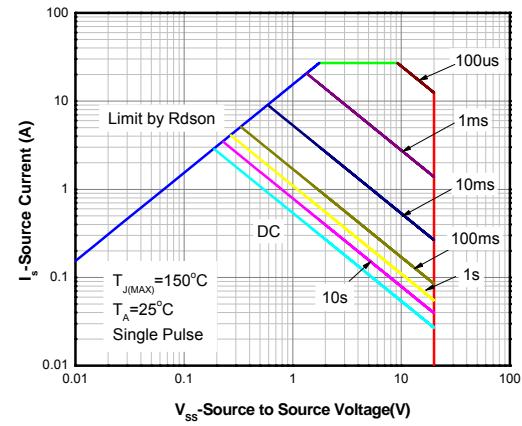
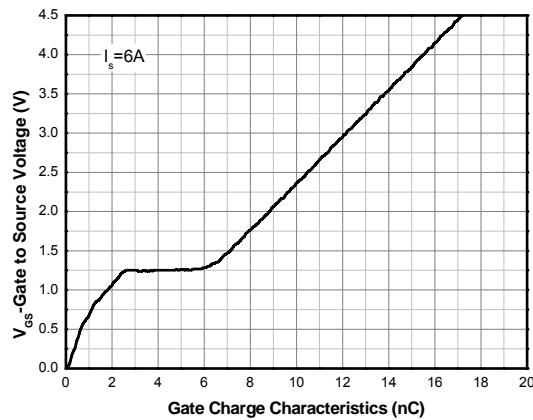
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Source to Source Voltage	BV <sub>SSS</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =1mA	20			V
Zero Gate Voltage Drain Current	I <sub>SSS</sub>	V <sub>SS</sub> =16V, V <sub>GS</sub> =0V Test Circuit 1			1	uA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>SS</sub> =0V, V <sub>GS</sub> =±12V Test Circuit 2			±10	uA
		V <sub>SS</sub> =0V, V <sub>GS</sub> =±5V Test Circuit 2			±1	uA
<b>ON CHARACTERISTICS</b>						
Gate to Source Cut-off Voltage	V <sub>GS(TH)</sub>	V <sub>SS</sub> =10V, I <sub>S</sub> =1mA Test Circuit 3	0.4	0.75	1.0	V
Source to Source On-state Resistance	R <sub>SS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>S</sub> =3.0A Test Circuit 5	26	38	48	mΩ
		V <sub>GS</sub> =4.0V, I <sub>S</sub> =3.0A Test Circuit 5	27	39	49	
		V <sub>GS</sub> =3.1V, I <sub>S</sub> =3.0A Test Circuit 5	29	42	56	
		V <sub>GS</sub> =2.5V, I <sub>S</sub> =3.0A Test Circuit 5	31	46	66	
<b>CHARGES, CAPACITANCES AND GATE RESISTANCE</b>						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> =0 V, f=1kHz, V <sub>SS</sub> =10 V Test Circuit 7		1210		pF
Output Capacitance	C <sub>OSS</sub>			149		
Reverse Transfer Capacitance	C <sub>RSS</sub>			135		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>G1S1</sub> =4.5 V, V <sub>SS</sub> =10V, I <sub>S</sub> =6A		17.3		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>			1.10		
Gate-to-Source Charge	Q <sub>GS</sub>			2.55		
Gate-to-Drain Charge	Q <sub>GD</sub>			2.90		
<b>SWITCHING CHARACTERISTICS</b>						
Turn-On Delay Time	t <sub>d(ON)</sub>	V <sub>GS</sub> =4.5V, V <sub>SS</sub> =10V, R <sub>L</sub> =3.3Ω, I <sub>S</sub> =3A, R <sub>G</sub> =6Ω Test Circuit 8		500		ns
Rise Time	t <sub>r</sub>			1310		
Turn-Off Delay Time	t <sub>d(OFF)</sub>			8160		
Fall Time	t <sub>f</sub>			3600		
<b>BODY DIODE CHARACTERISTICS</b>						
Forward Voltage	V <sub>F(S-S)</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =3.0A Test Circuit 6		0.8	1.2	V

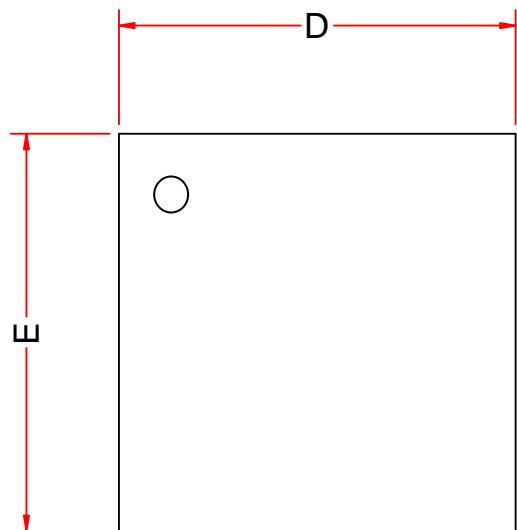
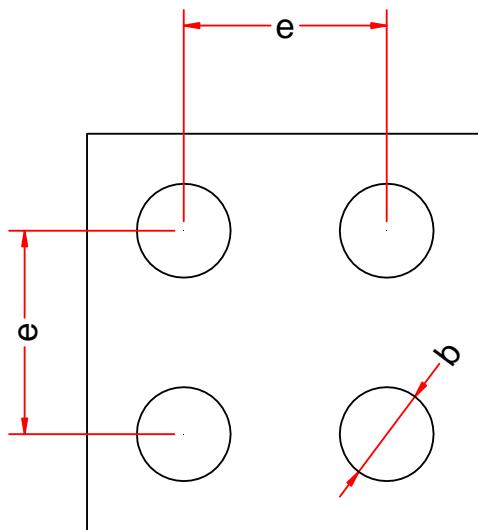
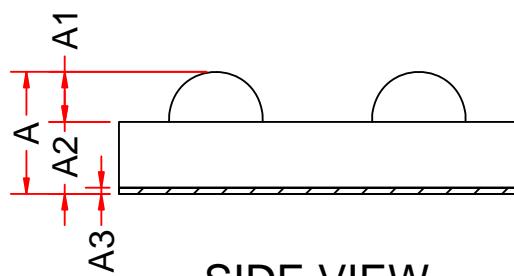
## Test Circuit

FET1 and the FET2 are both measured. Test circuits are example of measuring the FET1 side



**Typical Characteristics ( $T_A=25^\circ\text{C}$ , unless otherwise noted)**

**Output Characteristics<sup>d</sup>**
**Transfer Characteristics<sup>d</sup>**

**On-Resistance vs. Source Current<sup>d</sup>**
**On-Resistance vs. Gate-to-Source Voltage<sup>d</sup>**

**On-Resistance vs. Junction Temperature<sup>d</sup>**
**Threshold Voltage vs. Temperature**

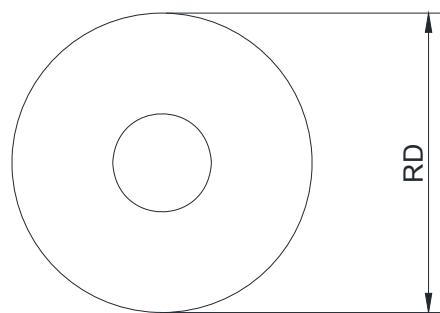

**Capacitance**

**Body Diode Forward Voltage <sup>d</sup>**

**Single Pulse power**

**Safe Operating Power**

**Gate Charge Characteristics**

**Package Outline Dimensions**
**CSP-4L**

**TOP VIEW**

**BOTTOM VIEW**

**SIDE VIEW**

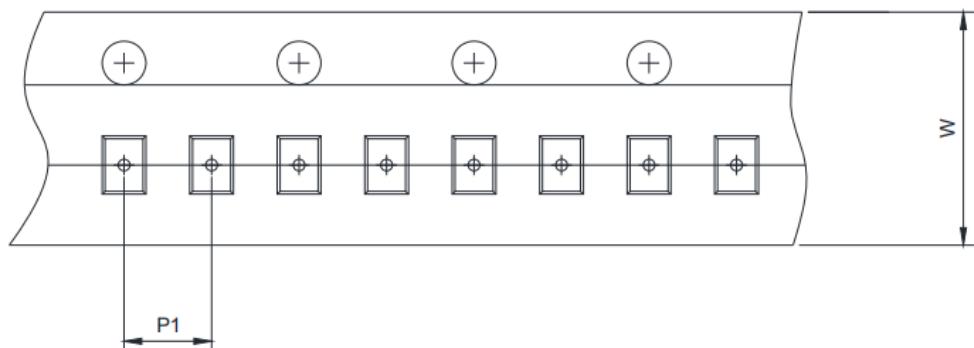
Symbol	Dimensions in Millimeters		
	Min.	Typ.	Max.
A	0.27	0.32	0.37
A1	0.06	0.09	0.11
A2	0.21	0.23	0.26
A3	0.025 Typ.		
D	1.44	1.47	1.50
E	1.44	1.47	1.50
e1	0.65 Typ.		
e2	0.65 Typ.		
b	0.28	0.30	0.32

## Tape and Reel Information

**Reel Dimensions**



**Tape Dimensions**



**Quadrant Assignments For PIN1 Orientation In Tape**



RD	Reel Dimension	<input checked="" type="checkbox"/> 7inch <input type="checkbox"/> 13inch
W	Overall width of the carrier tape	<input checked="" type="checkbox"/> 8mm <input type="checkbox"/> 12mm <input type="checkbox"/> 16mm
P1	Pitch between successive cavity centers	<input type="checkbox"/> 2mm <input checked="" type="checkbox"/> 4mm <input type="checkbox"/> 8mm
Pin1	Pin1 Quadrant	<input checked="" type="checkbox"/> Q1 <input type="checkbox"/> Q2 <input type="checkbox"/> Q3 <input type="checkbox"/> Q4